

Notice of References Cited			Application/Control No.	Applicant(s)/Patent Under Reexamination	
			10/634,906	TAKEUCHI ET AL.	
Examiner (Nancy) Thanh-Nhan P Nguyen			Art Unit 2871	Page 1 of 1	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0214625	11-2003	Arakawa et al.	349/194
	B	US-6,825,902	11-2004	Kaneko, Yasushi	349/114
	C	US-6,338,902	01-2002	Hsu et al.	428/412
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP-2001-091741	04-2001	Japan	Ichihashi et al	G02F 1/13363
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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